

	Type	Hits	Search Text	DBs
1	BRS	56802	((scan\$4 gate) ADJ line)	USPAT; US-PGPU B; EPO; JPO
2	BRS	93844	short\$3 ADJ (defect circuit fail\$4)	USPAT; US-PGPU B; EPO; JPO
3	BRS	418	349/54 349/192	USPAT; US-PGPU B; EPO; JPO
4	BRS	27691	(cut\$4 with laser) or (laser ADJ cut\$4)	USPAT; US-PGPU B; EPO; JPO
5	BRS	16	(cut\$4 with lazer) lazer ADJ cut\$4	USPAT; US-PGPU B; EPO; JPO
6	BRS	143	((scan\$4 gate) ADJ line)) and (short\$3 ADJ (defect circuit fail\$4)) and ((cut\$4 with laser) or (laser ADJ cut\$4))	USPAT; US-PGPU B; EPO; JPO
7	BRS	48	(349/54 349/192) and (short\$3 ADJ (defect circuit fail\$4)) and ((cut\$4 with laser) or (laser ADJ cut\$4))	USPAT; US-PGPU B; EPO; JPO
8	BRS	5214	(repair\$3 correct\$3) with insulat\$3	USPAT; US-PGPU B; EPO; JPO
9	BRS	52	((scan\$4 gate) ADJ line)) and (short\$3 ADJ (defect circuit fail\$4)) and ((repair\$3 correct\$3) with insulat\$3)	USPAT; US-PGPU B; EPO; JPO
10	BRS	93844	short\$3 ADJ (defect circuit fail\$4)	USPAT; US-PGPU B; EPO; JPO
11	BRS	1161	(short\$3 ADJ (defect circuit fail\$4)) same (detect\$3 and stor\$3)	USPAT; US-PGPU B; EPO; JPO

	Type	Hits	Search Text	DBs
12	BRS	418	349/54 349/192	USPAT; US-PGPU B; EPO; JPO
13	BRS	9	((short\$3 ADJ (defect circuit fail\$4)) same (detect\$3 and stor\$3)) and (349/54 349/192)	USPAT; US-PGPU B; EPO; JPO
14	BRS	1161	((short\$3 ADJ (defect circuit fail\$4)) same (detect\$3 and stor\$3)) and (short\$3 ADJ (defect circuit fail\$4))	USPAT; US-PGPU B; EPO; JPO
15	BRS	53	((scan\$4 gate) ADJ line) and (((short\$3 ADJ (defect circuit fail\$4)) same (detect\$3 and stor\$3)) and (short\$3 ADJ (defect circuit fail\$4)))	USPAT; US-PGPU B; EPO; JPO
16	BRS	2	heat ADJ cur\$3 and (349/54 349/192)	USPAT; US-PGPU B; EPO; JPO